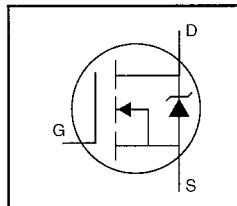


HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements

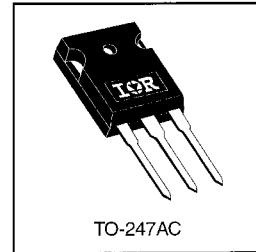


$V_{DSS} = 900V$
 $R_{DS(on)} = 2.5\Omega$
 $I_D = 4.7A$

Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

**Absolute Maximum Ratings**

Parameter		Max.	Units
$I_D @ T_c = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	4.7	A
$I_D @ T_c = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	2.9	
I_{DM}	Pulsed Drain Current ①	19	
$P_D @ T_c = 25^\circ C$	Power Dissipation	150	W
	Linear Derating Factor	1.2	W/ $^\circ C$
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy ②	500	mJ
I_{AR}	Avalanche Current ①	4.7	A
E_{AR}	Repetitive Avalanche Energy ①	15	mJ
dv/dt	Peak Diode Recovery dv/dt ③	1.5	V/ns
T_J	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$
T_{STG}	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	—	0.83	$^\circ C/W$
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	—	0.24	—	
$R_{\theta JA}$	Junction-to-Ambient	—	—	40	

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	900	—	—	V	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	1.0	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D=1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	2.5	Ω	$V_{GS}=10\text{V}$, $I_D=2.8\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$
g_{fs}	Forward Transconductance	2.5	—	—	S	$V_{DS}=50\text{V}$, $I_D=2.8\text{A}$ ④
I_{DS}	Drain-to-Source Leakage Current	—	—	100	μA	$V_{DS}=900\text{V}$, $V_{GS}=0\text{V}$
		—	—	500		$V_{DS}=720\text{V}$, $V_{GS}=0\text{V}$, $T_J=125^\circ\text{C}$
I_{GS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS}=20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS}=-20\text{V}$
Q_g	Total Gate Charge	—	—	120	nC	$I_D=4.7\text{A}$
Q_{gs}	Gate-to-Source Charge	—	—	16		$V_{DS}=360\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	67		$V_{GS}=10\text{V}$ See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	15	—		$V_{DD}=450\text{V}$
t_r	Rise Time	—	36	—	ns	$I_D=4.7\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	110	—		$R_G=9.1\Omega$
t_f	Fall Time	—	32	—		$R_D=95\Omega$ See Figure 10 ④
L_D	Internal Drain Inductance	—	5.0	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	13	—		
C_{iss}	Input Capacitance	—	1600	—	pF	$V_{GS}=0\text{V}$
C_{oss}	Output Capacitance	—	180	—		$V_{DS}=25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	63	—		$f=1.0\text{MHz}$ See Figure 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I_S	Continuous Source Current (Body Diode)	—	—	4.7	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	19		
V_{SD}	Diode Forward Voltage	—	—	1.8	V	$T_J=25^\circ\text{C}$, $I_S=4.7\text{A}$, $V_{GS}=0\text{V}$ ④
t_{rr}	Reverse Recovery Time	—	510	770	ns	$T_J=25^\circ\text{C}$, $I_F=4.7\text{A}$
Q_{rr}	Reverse Recovery Charge	—	2.2	3.3	μC	$dI/dt=100\text{A}/\mu\text{s}$ ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

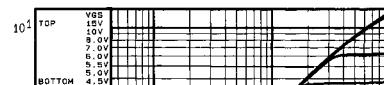
① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)

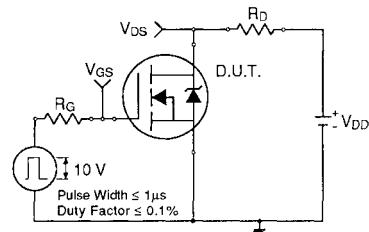
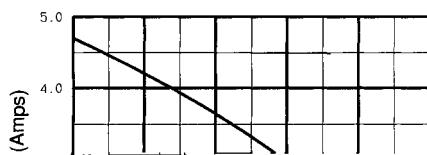
③ $I_{SD}\leq 4.7\text{A}$, $dI/dt\leq 110\text{A}/\mu\text{s}$, $V_{DD}\leq 600\text{V}$, $T_J\leq 150^\circ\text{C}$

② $V_{DD}=50\text{V}$, starting $T_J=25^\circ\text{C}$, $L=42\text{mH}$
 $R_G=25\Omega$, $I_{AS}=4.7\text{A}$ (See Figure 12)

④ Pulse width $\leq 300\ \mu\text{s}$; duty cycle $\leq 2\%$.







IRFPF40

